Probe Software

Software for MicroAnalysis

Probe for EPMA

Probe Image

PictureSnapApp

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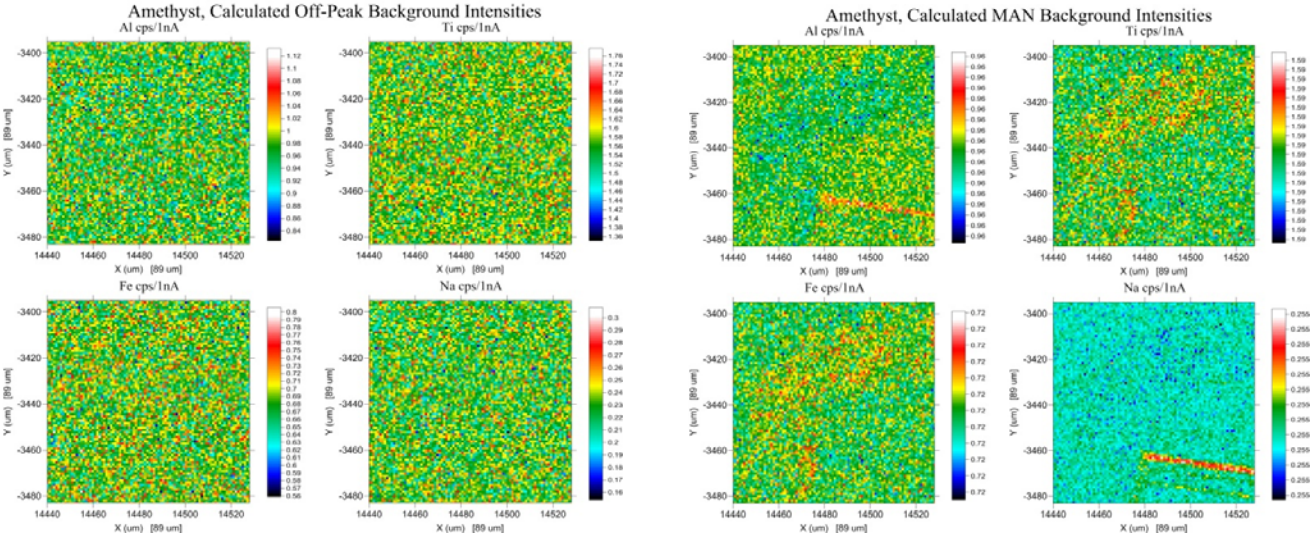
Improving Precision and Accuracy in Half the Time!

Utilizing Mean Atomic Number (MAN) Background Corrections for Trace Element Mapping

- The MAN background correction method can routinely perform background corrections on points and x-ray map pixels with an accuracy of approximately 100 to 200 PPM in silicates and oxides. By combining this time saving background correction technique with the "blank" correction (for



materials with a suitable blank standard, e.g., pure elements, oxides, simple silicates, etc.), we can further improve the MAN background correction accuracy to the level of the measured precision. And in half the acquisition time of using off-peak corrections!

Utilizing "Shared" Off-Peak Backgrounds from Other Elements on the Same Spectrometer

- By utilizing new "multi-point background" (MPB) code, Probe for EPMA can automatically apply off-peak background measurements from other elements on the same spectrometer (and same analyzing crystal) over an extended spectrometer range. This post-processing technique can improve the accuracy of traditional off-peak background measurements by allowing the user to fit the measured continuum intensity curvature in addition to determining the actual background slope with greater accuracy than using a single pair of traditional off-peak measurements.